TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE (π-MOSIII)

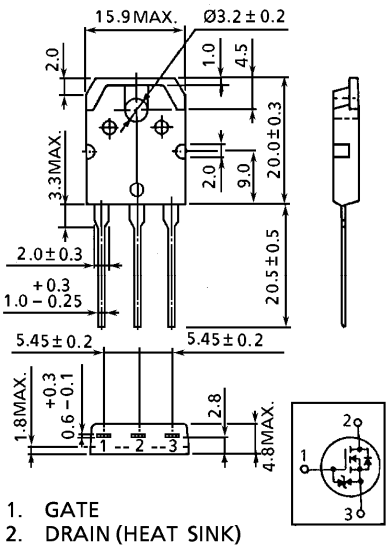
2SK2611

HIGH SPEED, HIGH VOLTAGE SWITCHING APPLICATIONS

DC-DC CONVERTER, RELAY DRIVE AND MOTOR DRIVE APPLICATIONS

INDUSTRIAL APPLICATIONS

Unit in mm



1. GATE
2. DRAIN (HEAT SINK)
3. SOURCE

JEDEC	—
EIAJ	SC-65
TOSHIBA	2-16C1B

Weight : 4.6g

- Low Drain-Source ON Resistance : $R_{DS\,(ON)}=1.1\Omega$ (Typ.)
- High Forward Transfer Admittance : $|Y_{fs}|=7.0S$ (Typ.)
- Low Leakage Current : $I_{DSS}=100\mu A$ (Max.) ($V_{DS}=720V$)
- Enhancement-Mode : $V_{th}=2.0\sim4.0V$ ($V_{DS}=10V$, $I_D=1mA$)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Drain-Source Voltage		V_{DSS}	900	V
Drain-Gate Voltage ($R_{GS}=20k\Omega$)		V_{DGR}	900	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	DC	I_D	9	A
	Pulse	I_{DP}	27	A
Drain Power Dissipation (Tc=25°C)		P_D	150	W
Single Pulse Avalanche Energy**		E_{AS}	663	mJ
Avalanche Current		I_{AR}	9	A
Repetitive Avalanche Energy*		E_{AR}	15	mJ
Channel Temperature		T_{ch}	150	°C
Storage Temperature Range		T_{stg}	−55~150	°C

THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Case	$R_{th\,(ch-c)}$	0.833	°C / W
Thermal Resistance, Channel to Ambient	$R_{th\,(ch-a)}$	50	°C / W

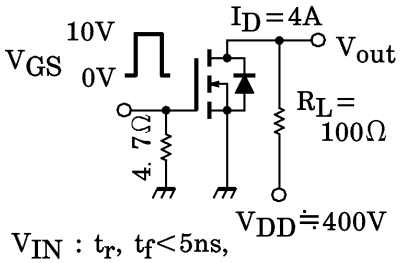
Note ;

* Repetitive rating ; Pulse Width Limited by Max. junction temperature.

** $V_{DD}=90V$, $T_{ch}=25°C$ (initial), $L=15mH$
$R_G=25\Omega$, $I_{AR}=9A$

This transistor is an electrostatic sensitive device.
Please handle with caution.

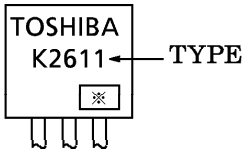
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GSS}	$V_{GS}=\pm30V$, $V_{DS}=0V$	—	—	±10	μA
Gate-Source Breakdown Voltage		$V_{(BR)\,GSS}$	$I_G=\pm10\mu A$, $V_{DS}=0V$	±30	—	—	V
Drain Cut-off Current		I_{DSS}	$V_{DS}=720V$, $V_{GS}=0V$	—	—	100	μA
Drain-Source Breakdown Voltage		$V_{(BR)\,DSS}$	$I_D=10mA$, $V_{GS}=0V$	900	—	—	V
Gate Threshold Voltage		V_{th}	$V_{DS}=10V$, $I_D=1mA$	2.0	—	4.0	V
Drain-Source ON Resistance		$R_{DS\,(ON)}$	$V_{GS}=10V$, $I_D=4A$	—	1.1	1.4	Ω
Forward Transfer Admittance		$\|Y_{fs}\|$	$V_{DS}=15V$, $I_D=4A$	3.0	7.0	—	S
Input Capacitance		C_{iss}	$V_{DS}=25V$, $V_{GS}=0V$, f=1MHz	—	2040	—	pF
Reverse Transfer Capacitance		C_{rss}		—	45	—	
Output Capacitance		C_{oss}		—	190	—	
Switching Time	Rise Time	t_r		—	25	—	ns
	Turn-on Time	t_{on}		—	60	—	
	Fall Time	t_f		—	20	—	
	Turn-off Time	t_{off}		—	95	—	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q_g	$V_{DD}\fallingdotseq400V$, $V_{GS}=10V$, $I_D=9A$	—	58	—	nC
Gate-Source Charge		Q_{gs}		—	32	—	
Gate-Drain ("Miller") Charge		Q_{gd}		—	26	—	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	I_{DR}	—	—	—	9	A
Pulse Drain Reverse Current	I_{DRP}	—	—	—	27	A
Diode Forward Voltage	V_{DSF}	$I_{DR}=9A$, $V_{GS}=0V$	—	—	−1.9	V
Reverse Recovery Time	t_{rr}	$I_{DR}=9A$, $V_{GS}=0V$	—	1.6	—	μs
Reverse Recovery Charge	Q_{rr}	$dI_{DR}/dt=100A/\mu s$	—	20	—	μC

MARKING



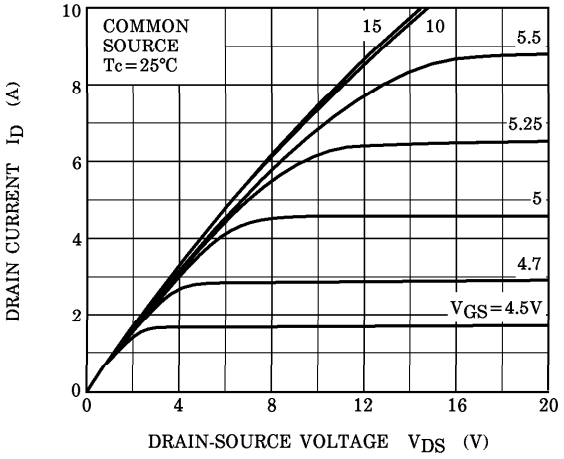
TYPE

※ Lot Number

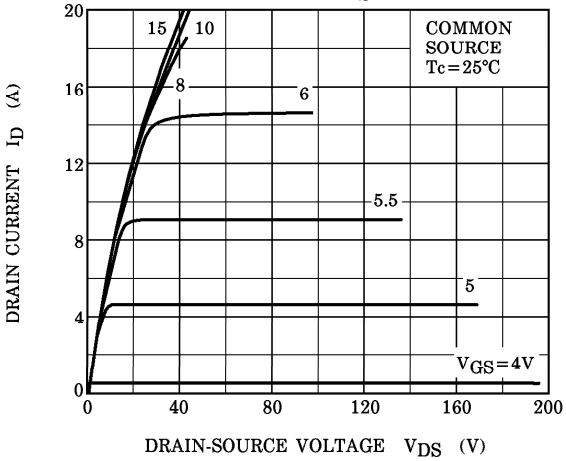
□□ — Month (Starting from Alphabet A)

Year (Last Number of the Christian Era)

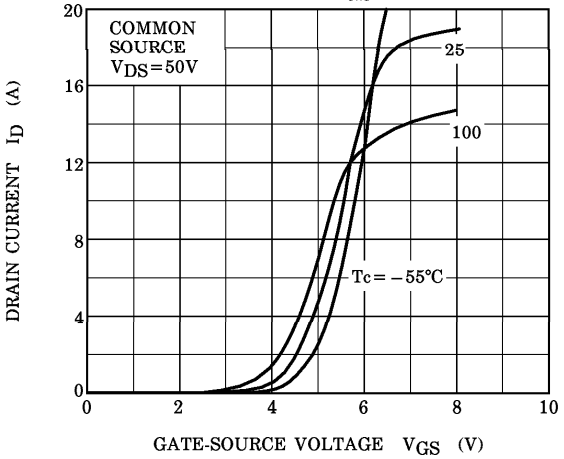
$I_D - V_{DS}$



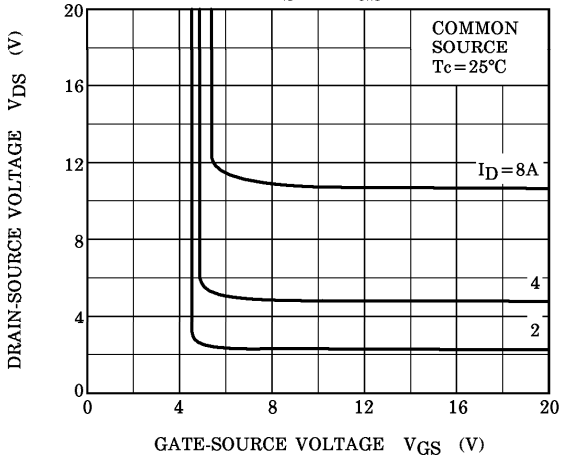
$I_D - V_{DS}$



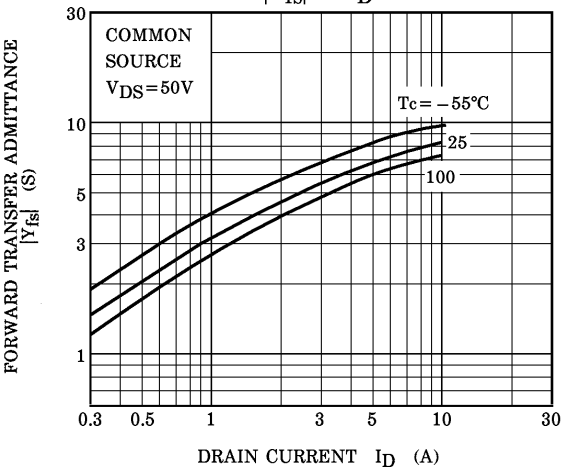
$I_D - V_{GS}$



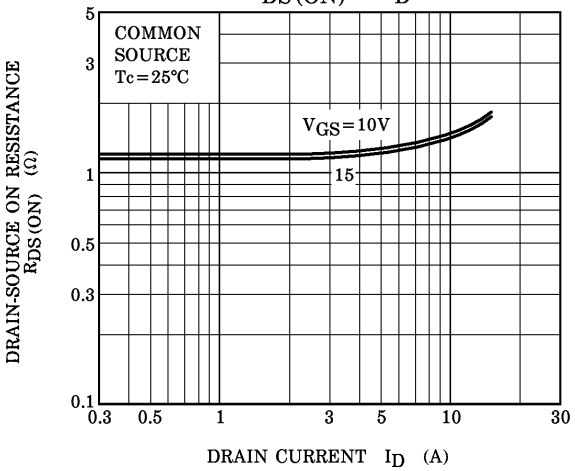
$V_{DS} - V_{GS}$



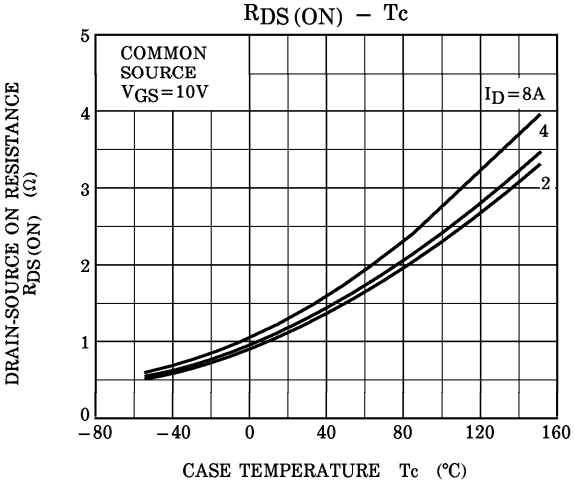
$|Y_{fs}| - I_D$



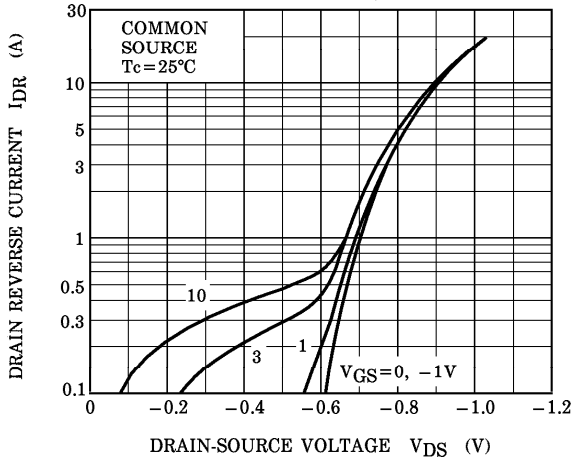
$R_{DS\,(ON)} - I_D$



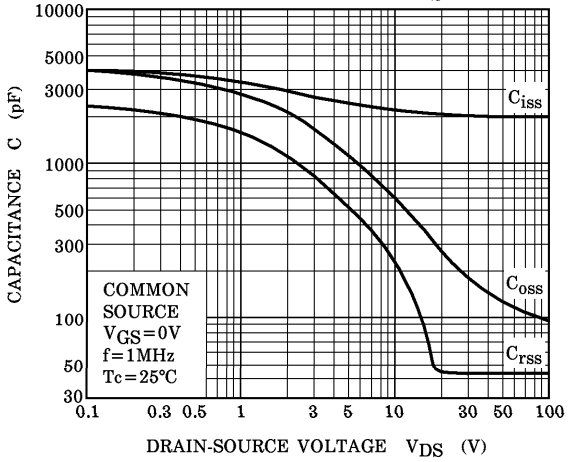
$R_{DS(ON)}$ – Tc



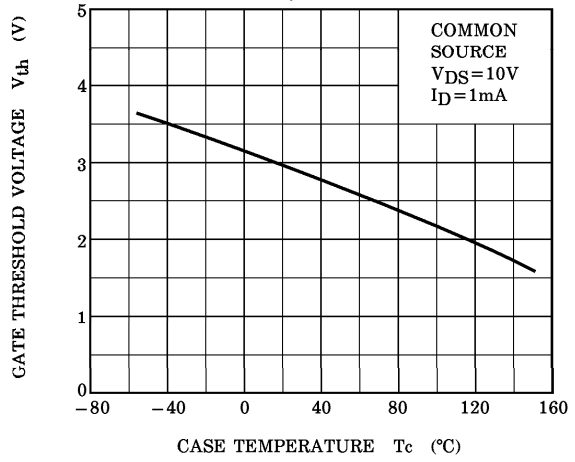
I_{DR} – V_{DS}



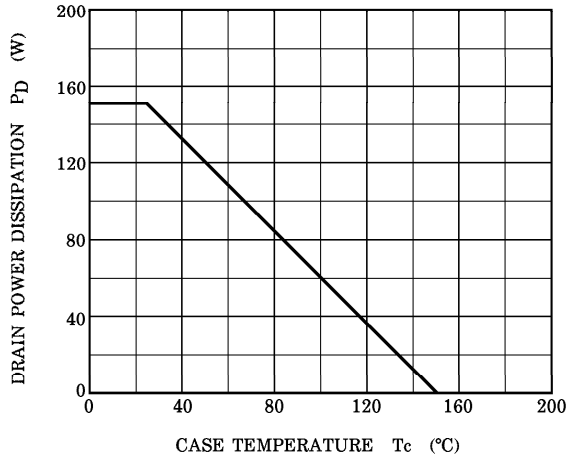
CAPACITANCE – V_{DS}



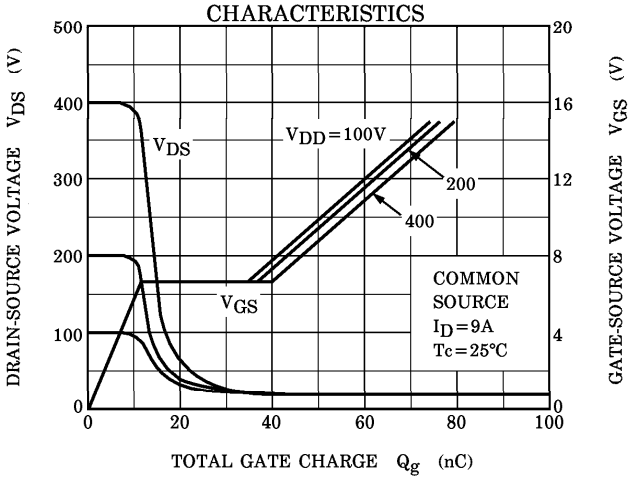
V_{th} – Tc



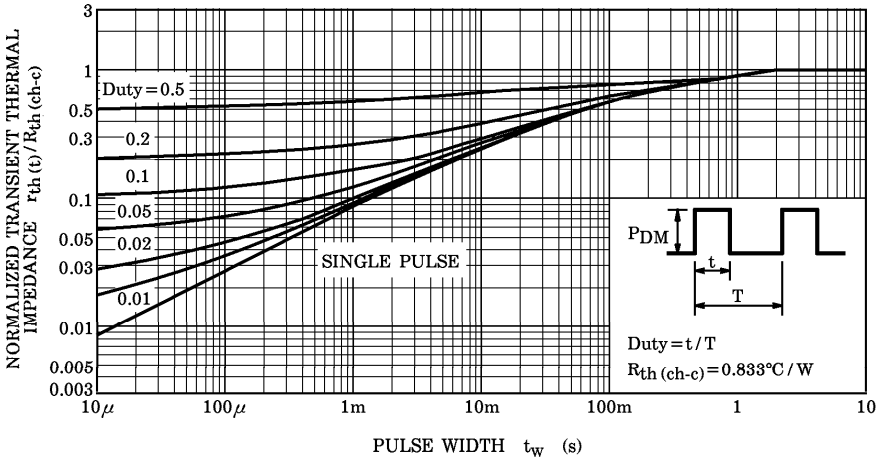
P_D – Tc



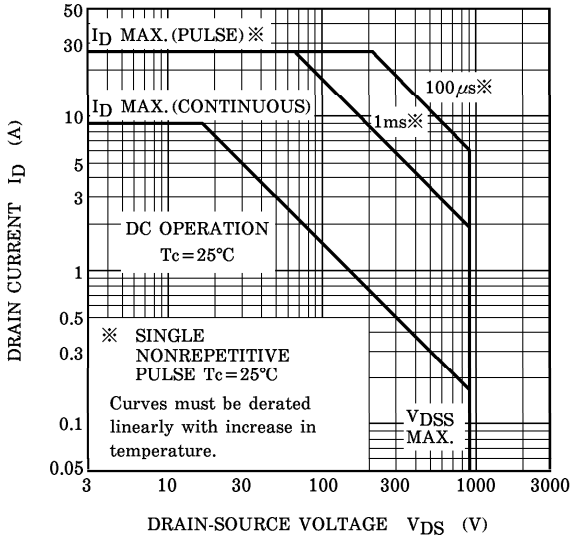
DYNAMIC INPUT / OUTPUT CHARACTERISTICS



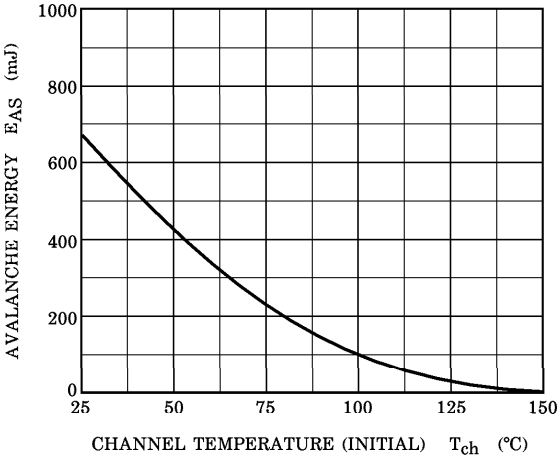
r_{th} – t_w

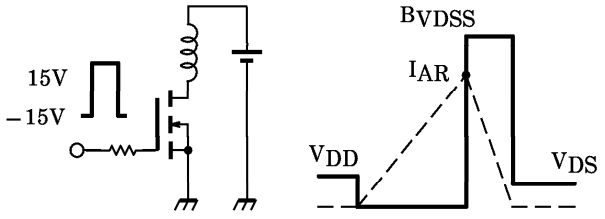


SAFE OPERATING AREA



E_{AS} – T_{ch}





TEST CIRCUIT WAVE FORM

Peak I_{AR} = 9A, R_G = 25Ω
V_{DD} = 90V, L = 15mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$